Notice of References Cited Application/Control No. 10/580,401 Examiner AWET HAILE Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0059432 A1	05-2002	Masuda et al.	709/227
*	В	US-2003/0076829 A1	04-2003	Rabie et al.	370/391
*	С	US-2004/0202159 A1	10-2004	Matsubara et al.	370/389
*	D	US-2006/0182119 A1	08-2006	Li et al.	370/395.52
*	Е	US-7,215,640 B2	05-2007	Matsubara, Daisuke	370/235
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.